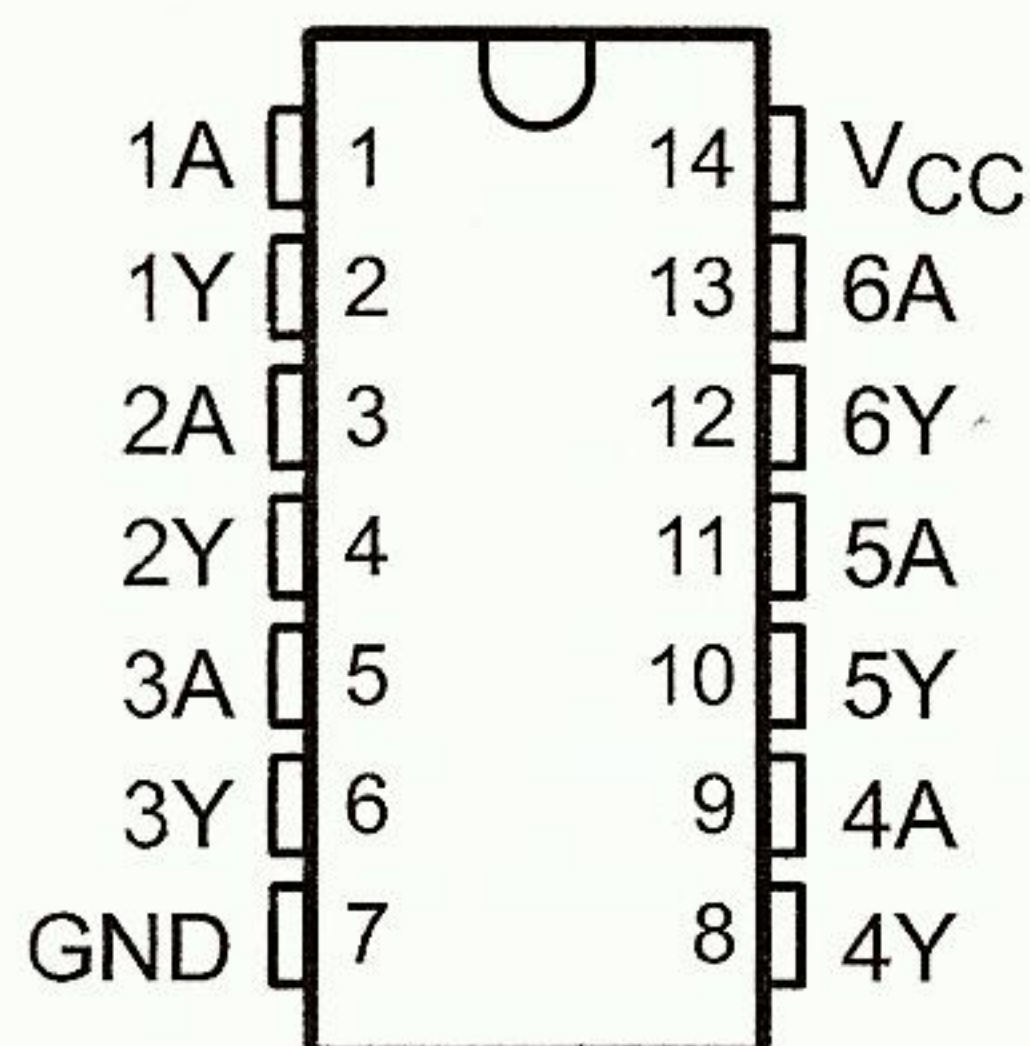
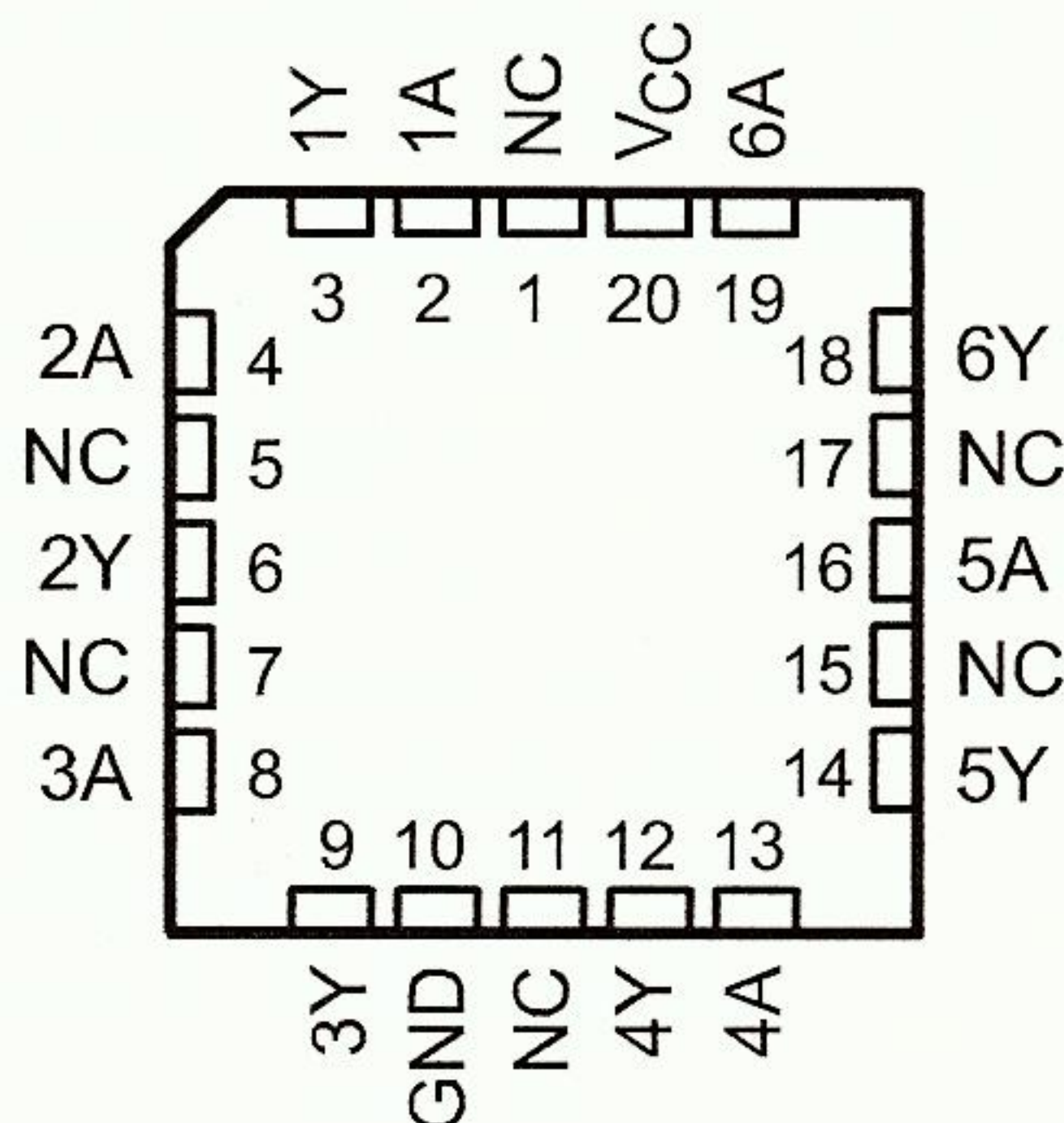


- Wide Operating Voltage Range of 2 V to 6 V
- Outputs Can Drive Up To 10 LSTTL Loads
- Low Power Consumption, 20- $\mu$ A Max  $I_{CC}$
- Typical  $t_{pd} = 7$  ns
- $\pm 4$ -mA Output Drive at 5 V
- Low Input Current of 1  $\mu$ A Max
- Unbuffered Outputs

SN54HCU04 ... J OR W PACKAGE  
SN74HCU04 ... D, DB, N, NS, OR PW PACKAGE  
(TOP VIEW)



SN54HCU04 ... FK PACKAGE  
(TOP VIEW)



NC – No internal connection

description/ordering information

The 'HCU04 devices contain six independent inverters. They perform the Boolean function  $Y = \bar{A}$  in positive logic.

ORDERING INFORMATION

$T_A$	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	PDIP – N	Tube of 25	SN74HCU04N	SN74HCU04N
		Tube of 50	SN74HCU04D	HCU04
	SOIC – D	Reel of 2500	SN74HCU04DR	
		Reel of 250	SN74HCU04DT	
	SOP – NS	Reel of 2000	SN74HCU04NSR	HCU04
	SSOP – DB	Reel of 2000	SN74HCU04DBR	HU04
	TSSOP – PW	Reel of 90	SN74HCU04PW	HCU04
		Reel of 2000	SN74HCU04PWR	
		Reel of 250	SN74HCU04PWT	
-55°C to 125°C	CDIP – J	Tube of 25	SNJ54HCU04J	SNJ54HCU04J
	CFP – W	Tube of 150	SNJ54HCU04W	SNJ54HCU04W
	LCCC – FK	Tube of 55	SNJ54HCU04FK	SNJ54HCU04FK

† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at [www.ti.com/sc/package](http://www.ti.com/sc/package).



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TEXAS  
INSTRUMENTS

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